

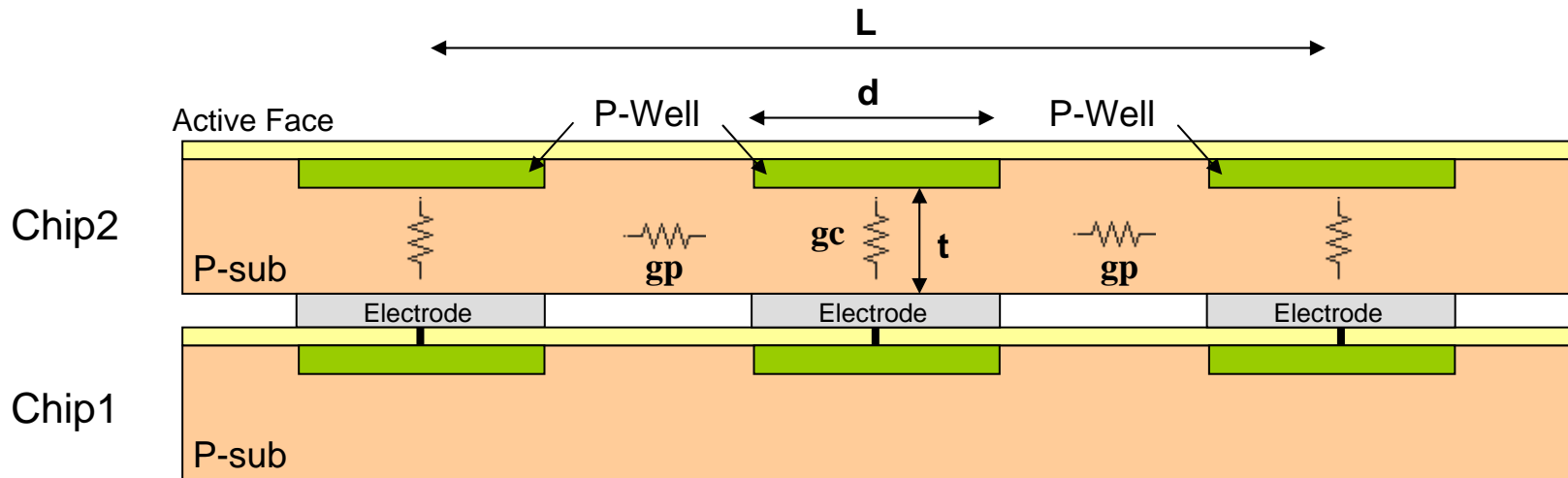
Signal Transmission method between stacked chips with resistive-coupling (Patented in Japan)

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Sorbus Memory, Inc.

Signal transmission through the substrate resistance

Coupling from chip1 to chip2 through the **backside electrode** of chip2 and the **substrate resistance** of chip1. (VDD/VSS are supplied from wire-bonding or TSV.)



$$g_c = \pi d^2 / (4 \rho_{sub} \cdot t)$$

$$2g_p = 2 \pi t / (\rho_{sub} \cdot \ln(L/d))$$

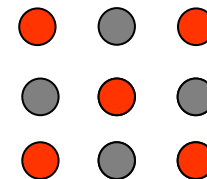
$$g_c / g_p = (d / 2t)^2 \cdot \ln(L/d)$$

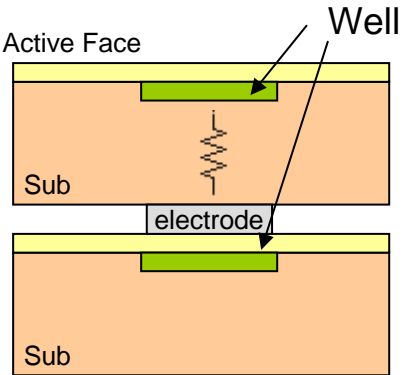
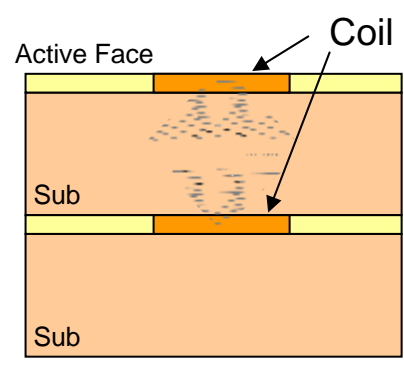
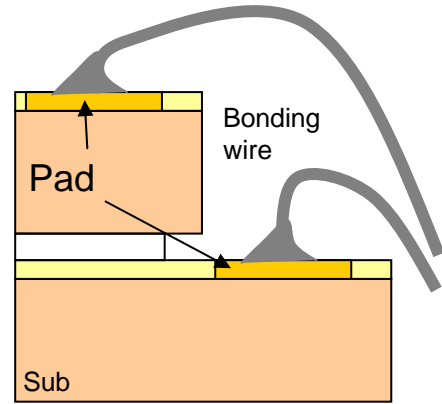
g_c, g_p : conductance
 ρ_{sub} : sub resistivity

Voltage transfer coefficient
 $A_v = 1 / \{1 + (g_c/g_p)^{-1}\}$

$A_v \doteq 0.5$ at $d=2t, L=3d$

Should operate alternately



	Substrate Resistive-Coupling	Inductive-Coupling	Wire-Bonding
Structure	 <p>Active Face Well Sub electrode Sub</p>	 <p>Active Face Coil Sub Sub</p>	 <p>Bonding wire Pad Sub Sub</p>
Power	<p>⊙ ≐1.1mW</p>	<p>× ≐2.8~6.0mW</p>	<p>△ ≐3.0mW</p>
Voltage Transfer coefficient	<p>○ ≐0.5</p>	<p>× <0.1</p>	<p>○ 1.0 (0.5, if terminated)</p>
Frequency Characteristic	<p>⊙ ≐2GHz</p>	<p>△ ≐1GHz</p>	<p>△ ≐1GHz</p>
Layout Flexibility	<p>⊙</p>	<p>⊙</p>	<p>×</p>